Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/539,421	MITSUI, YASUHIRO	
Examiner	Art Unit	
Fllen C. Tran	2134	

SEARCHED				
Class	Subclass	Date	Examiner	
713	176	8/19/2005	ECT	
380	28	8/19/2005	ECT	
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PALM, INVENTOR	3/13/2006	ECT
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	8/22/2006	ECT
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